

# **2020 IEEE European Test Symposium (ETS 2020)**

**Tallinn, Estonia  
25 – 29 May 2020**



**IEEE Catalog Number: CFP20216-POD**  
**ISBN: 978-1-7281-4313-2**

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IEEE Catalog Number:	CFP20216-POD
ISBN (Print-On-Demand):	978-1-7281-4313-2
ISBN (Online):	978-1-7281-4312-5
ISSN:	1530-1877

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# TABLE OF CONTENTS

<b>ANALOG FAULT SIMULATION - A HOT TOPIC!</b> .....	1
<i>Stephen Sunter</i>	
<b>DEVICE-AWARE TEST FOR EMERGING MEMORIES: ENABLING YOUR TEST PROGRAM FOR DPPB LEVEL</b> .....	6
<i>Lizhou Wu ; Moritz Fieback ; Mottaqiallah Taouil ; Said Hamdioui</i>	
<b>DESIGN, VERIFICATION, TEST AND IN-FIELD IMPLICATIONS OF APPROXIMATE COMPUTING SYSTEMS</b> .....	8
<i>A. Bosio ; S. Di Carlo ; P. Girard ; E. Sanchez ; A. Savino ; L. Sekanina ; M. Traiola ; Z. Vasicek ; A. Virazel</i>	
<b>TEST SEQUENCE-OPTIMIZED BIST FOR AUTOMOTIVE APPLICATIONS</b> .....	18
<i>Bartosz Kaczmarek ; Grzegorz Mrugalski ; Nilanjan Mukherjee ; Janusz Rajski ; Lukasz Rybak ; Jerzy Tyszer</i>	
<b>DYNAMIC AUTHENTICATION-BASED SECURE ACCESS TO TEST INFRASTRUCTURE</b> .....	24
<i>Michele Portolan ; Vincent Reynaud ; Paolo Maistri ; Regis Leveugle</i>	
<b>MINIMAL WITNESSES FOR SECURITY WEAKNESSES IN RECONFIGURABLE SCAN NETWORKS</b> .....	30
<i>Pascal Raiola ; Tobias Paxian ; Bernd Becker</i>	
<b>TESTING SCOUTING LOGIC-BASED COMPUTATION-IN-MEMORY ARCHITECTURES</b> .....	36
<i>Moritz Fieback ; Surya Nagarajan ; Rajendra Bishnoi ; Mehdi Tahoori ; Mottaqiallah Taouil ; Said Hamdioui</i>	
<b>DEFECT CHARACTERIZATION AND TEST GENERATION FOR SPINTRONIC-BASED COMPUTE-IN-MEMORY</b> .....	42
<i>Sarath Mohanachandran Nair ; Christopher Münch ; Mehdi B. Tahoori</i>	
<b>MBIST SUPPORT FOR RELIABLE EMRAM SENSING</b> .....	48
<i>Jongsin Yun ; Benoit Nadeau-Dostie ; Martin Keim ; Cyrille Dray ; Mehdi Boujamaa</i>	
<b>TIGHTENING THE MESH SIZE OF THE CELL-AWARE ATPG NET FOR CATCHING ALL DETECTABLE WEAKEST FAULTS</b> .....	54
<i>Min-Chun Hu ; Zhan Gao ; Santosh Malagi ; Joe Swenton ; Jos Huisken ; Kees Goossens ; Cheng-Wen Wu ; Erik Jan Marinissen</i>	
<b>VARIATION-AWARE DEFECT CHARACTERIZATION AT CELL LEVEL</b> .....	60
<i>Zahra Paria Najafi-Haghi ; Marzieh Hashemipour-Nazari ; Hans-Joachim Wunderlich</i>	
<b>FUNCTIONAL-LIKE TRANSITION DELAY FAULT TEST-PATTERN GENERATION USING A BAYESIAN-BASED CIRCUIT MODEL</b> .....	66
<i>Ching-Yuan Chen ; Ching-Hong Cheng ; Jiun-Lang Huang ; Krishnendu Chakrabarty</i>	
<b>NONLINEAR CODES FOR CONTROL FLOW CHECKING</b> .....	72
<i>Giorgio Di Natale ; Osnat Keren</i>	
<b>QAMR: AN APPROXIMATION-BASED FULLY RELIABLE TMR ALTERNATIVE FOR AREA OVERHEAD REDUCTION</b> .....	78
<i>B. Deveautour ; M. Traiola ; A. Virazel ; P. Girard</i>	
<b>DETERMINED-SAFE FAULTS IDENTIFICATION: A STEP TOWARDS ISO26262 HARDWARE COMPLIANT DESIGNS</b> .....	84
<i>Felipe Augusto Da Silva ; Ahmet Cagri Bagbaba ; Sandro Sartoni ; Riccardo Cantoro ; Matteo Sonza Reorda ; Said Hamdioui ; Christian Sauer</i>	
<b>ACCURATE MEASUREMENTS OF SMALL RESISTANCES IN VERTICAL INTERCONNECTS WITH SMALL ASPECT RATIOS</b> .....	90
<i>Michele Stucchi ; Ferenc Fodor ; Erik Jan Marinissen</i>	
<b>A BUILT-IN SELF-TEST METHOD FOR MEMS PIEZORESISTIVE SENSOR</b> .....	96
<i>Manhong Zhu ; Jia Li ; Weibing Wang ; Dapeng Chen</i>	
<b>THERMAL NEUTRONS: A POSSIBLE THREAT FOR SUPERCOMPUTERS AND SAFETY CRITICAL APPLICATIONS</b> .....	102
<i>Daniel Oliveira ; Sean Blanchard ; Nathan Debardeleben ; Fernando F. Dos Santos ; Gabriel Piscocya Dávila ; Philippe Navaux ; Carlo Cazzaniga ; Christopher Frost ; Robert C. Baumann ; Paolo Rech</i>	
<b>LATENT DEFECT SCREENING WITH VISUALLY-ENHANCED DYNAMIC PART AVERAGE TESTING</b> .....	108
<i>Anthony Coyette ; Wim Dobbelaere ; Ronny Vanhooren ; Nektar Xama ; Jhon Gomez ; Georges Gielen</i>	
<b>PWS: POTENTIAL WAFERMAP SCRATCH DEFECT PATTERN RECOGNITION WITH MACHINE LEARNING TECHNIQUES</b> .....	114
<i>Katherine Shu-Min Li ; Peter Yi-Yu Liao ; Leon Chou ; Ken Chau-Cheung Chen ; Andrew Yi-Ann Huang ; Sying-Jyan Wang ; Gus Chang-Hung Han</i>	

<b>AVOIDING MIXED-SIGNAL FIELD RETURNS BY OUTLIER DETECTION OF HARD-TO-DETECT DEFECTS BASED ON MULTIVARIATE STATISTICS.....</b>	120
<i>Nektar Xama ; Jakob Raymaekers ; Martin Andraud ; Jhon Gomez ; Wim Dobbelaere ; Ronny Vanhooren ; Anthony Coyette ; Georges Gielen</i>	
<b>THE RISK OF OUTSOURCING: HIDDEN SCA TROJANS IN THIRD-PARTY IP-CORES THREATEN CRYPTOGRAPHIC ICS.....</b>	126
<i>David Knichel ; Thorben Moos ; Amir Moradi</i>	
<b>MODELING STATIC NOISE MARGIN FOR FINFET BASED SRAM PUFs .....</b>	132
<i>Shayesteh Masoumian ; Georgios Selimis ; Roel Maes ; Geert-Jan Schrijen ; Said Hamdioui ; Mottaqiallah Taouil</i>	
<b>HARDWARE TROJAN ATTACKS IN ANALOG/MIXED-SIGNAL ICS VIA THE TEST ACCESS MECHANISM.....</b>	138
<i>Mohamed Elshamy ; Giorgio Di Natale ; Antonios Pavlidis ; Marie-Minerve Lou�rat ; Haralampos-G. Stratigopoulos</i>	
<b>LID-CAT: A LIGHTWEIGHT DETECTOR FOR CACHE ATTACKS.....</b>	144
<i>Cezar Reinbrecht ; Said Hamdioui ; Mottaqiallah Taouil ; Behrad Niazmand ; Tara Ghasempouri ; Jaan Raik ; Johanna Sep�lveda</i>	
<b>BUILT-IN PREDICTORS FOR DYNAMIC CROSSTALK AVOIDANCE.....</b>	150
<i>Rezgar Sadeghi ; Zainalabedin Navabi</i>	
<b>A NEW MONITOR INSERTION ALGORITHM FOR INTERMITTENT FAULT DETECTION.....</b>	156
<i>Hassan Ebrahimi ; Hans G. Kerkhoff</i>	
<b>ON-CHIP REDUCED-CODE STATIC LINEARITY TEST OF V<sub>CM</sub>-BASED SWITCHING SAR ADCS USING AN INCREMENTAL ANALOG-TO-DIGITAL CONVERTER .....</b>	162
<i>Renato S. Feitoza ; Manuel J. Barragan ; Antonio Gines ; Salvador Mir</i>	
<b>DIGITAL DEFECT BASED BUILT-IN SELF-TEST FOR LOW DROPOUT VOLTAGE REGULATORS .....</b>	164
<i>Mehmet Ince ; Sule Ozev</i>	
<b>MONITORING OF BTI AND HCI AGING IN SRAM DECODERS .....</b>	166
<i>Helen-Maria Dounavi ; Yiorgos Tsiatouhas</i>	
<b>G-PUF: AN INTRINSIC PUF BASED ON GPU ERROR SIGNATURES .....</b>	168
<i>Bruno Forlin ; Ronaldo Husemann ; Luigi Carro ; Cezar Reinbrecht ; Said Hamdioui ; Mottaqiallah Taouil</i>	
<b>A SIFT-BASED WAVEFORM CLUSTERING METHOD FOR AIDING ANALOG/MIXED- SIGNAL IC VERIFICATION.....</b>	170
<i>Andrei Gaita ; Georgian Nicolae ; Emilian C. David ; Andi Buzo ; Corneliu Burileanu ; Georg Pelz</i>	
<b>LEARNING-BASED CELL-AWARE DEFECT DIAGNOSIS OF CUSTOMER RETURNS.....</b>	172
<i>S. Mhamdi ; P. Girard ; A. Virazel ; A. Bosio ; A. Ladhar</i>	
<b>ANOMALY DETECTION IN EMBEDDED SYSTEMS USING POWER AND MEMORY SIDE CHANNELS .....</b>	174
<i>Jiho Park ; Virinchi Roy Surabhi ; Prashanth Krishnamurthy ; Siddharth Garg ; Ramesh Karri ; Farshad Khorrami</i>	
<b>AUTOMATED GRAPH-BASED FAULT INJECTION INTO VIRTUAL PROTOTYPES FOR ROBUSTNESS EVALUATION .....</b>	176
<i>Jo Laufenberg ; Thomas Kropf ; Oliver Bringmann</i>	
<b>EFFICIENT PROGNOSTICATION OF PATTERN COUNT WITH DIFFERENT INPUT COMPRESSION RATIOS .....</b>	178
<i>Fong-Jyun Tsai ; Chong-Siao Ye ; Yu Huang ; Kuen-Jong Lee ; Wu-Tung Cheng ; Sudhakar M. Reddy ; Mark Kassab ; Janusz Rajski</i>	
<b>FAILURE AND ATTACK DETECTION BY DIGITAL SENSORS.....</b>	180
<i>Md Toufiq Hasan Anik ; Rachit Saini ; Jean-Luc Danger ; Sylvain Guilley ; Naghmeh Karimi</i>	
<b>DETECTION OF ROWHAMMER ATTACKS IN SOCS WITH FPGAS .....</b>	182
<i>Rana Elnaggar ; Siyuan Chen ; Peilin Song ; Krishnendu Chakrabarty</i>	
<b>IEEE STD. P1687.1 FOR ACCESS CONTROL OF RECONFIGURABLE SCAN NETWORKS.....</b>	184
<i>Erik Larsson ; Zehang Xiang ; Prathamesh Murali</i>	
<b>DESIGN OBFUSCATION VERSUS TEST .....</b>	186
<i>Farimah Farahmandi ; Ozgur Sinanoglu ; Ronald Blanton ; Samuel Pagliarini</i>	
<b>LINKING CHIP, BOARD, AND SYSTEM TEST VIA STANDARDS .....</b>	196
<i>Michele Portolan ; Jeff Rearick ; Martin Keim</i>	
<b>PUF ENROLLMENT AND LIFE CYCLE MANAGEMENT: SOLUTIONS AND PERSPECTIVES FOR THE TEST COMMUNITY .....</b>	204
<i>Amir Ali Pour ; Vincent Berouille ; Bertrand Cambou ; Jean-Luc Danger ; Giorgio Di Natale ; David Hely ; Sylvain Guilley ; Naghmeh Karimi</i>	
<b>Author Index</b>	